S	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/695,057	DENG ET AL.
Examiner prum	Art Unit
Tod T. Van Roy	2828

SEARCHED			
Class	Subclass	Date	Examine
$\overline{}$			
$\overline{}$:		<u> </u>
	$\overline{}$		
			<u> </u>
		$\overline{}$	
			<u> </u>
		`	

ראו	ERFERENC	E SEARCH	IED
Clase	Subclass	Date	Examiner
•			

(INCLUDING SEARCH	DATE	EXMR
EAST tat seach	A0403	ne
\		
		_
		\